Erratum to: Electrical and Optical Characterization of Electron Beam Evaporated Indium Antimonide Thin Films

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Figure 7 has been published incorrectly in the original publication of the article. The correct version of the figure is provided below.

Fig. 7 Wavelength (nm) versus absorption spectrum of as deposited thin films for thickness **a** 700 nm, **b** 800 nm, **c** 900 nm, **d** 1,000 nm, **e** 1,100 nm

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